

<b>Notice of References Cited</b>	Application/Control No. 10/644,158	Applicant(s)/Patent Under Reexamination TOUTOUNCHI ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-6,678,645	01-2004	Rajsuman et al.	703/20
	D	US-6,532,440	03-2003	Boppana et al.	703/14
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#### NON-PATENT DOCUMENTS

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	U	Chakravarty, S., et al., "IDDQ measurement based diagnosis of bridging faults in full scan circuits", Febraury, 1993. Department of Computer Science, State University of New York at Buffalo, Technical Report No: 93-04. pgs. 1-12				
	V	Rajsuman, R., "IDDQ testing for CMOS VLSI", 4/2000. IEEE, pgs. 544-568.				
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	X	Chakravarty, S. et al., "Algorithms for current monitor based diagnosis of bridging and leakage faults", ACM/IEEE Design Automation Conference, pgs. 353-356.				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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